

Notice of References Cited

Application/Control No.
10/085,587

Applicant(s)/Patent Under
Reexamination
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Examiner
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Art Unit
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,434,714 B1	08-2002	Lewis et al.	714/38
	B	US-6,232,974 B1	05-2001	Horvitz et al.	345/419
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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